

Search Notes

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Examiner

Shih-wen Hsieh

Applicant(s)/Patent under
Reexamination

MURCIA ET AL.

Art Unit

2861

SEARCHED

Class	Subclass	Date	Examiner
347	22-24,28 29,30,32 33,35	3/22/2006	SWH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR